

Date Created : 2007/11/29  
Date Issued On : 2007/12/13  
PCN# : Q1070802-A

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

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Phone:

Implementation of change:  
Expected 1st Device Shipment Date: 2008/01/10

Earliest Year/Work Week of Changed Product: 0802

Change Type Description: Alternate Assembly/Test Location/Qualification

Description of Change (From): Currently being manufactured at SPS(SP Semiconductor & Communication Co Ltd.) in Korea

Description of Change (To): Qualify in Fairchild Semiconductor (Suzhou) Co., Ltd. China as an Alternate Assembly and Test for TO220F 5 leads. (There is no difference in package out line, process and bill of materials

Reason for Change : Qualification of alternate manufacturing site to improve capacity flexibility in response to changing customer business demand as well as enable better management on delivery and cycle-time.

Qual/REL Plan Numbers : Q20070495

Qualification :

Fairchild Semiconductor (Suzhou) Co., LTD (FSSZ) is being qualified as an additional assembly and test site as part of Fairchild Semiconductor's ongoing effort to increase manufacturing capacity for our various products assembled in the TO-220F-5L packages.

**Results/Discussion**

Test: (Autoclave)			
Lot	Device	96-HOURS	Failure Code
Q20070495AAACLV	FSCQ1565RTYDTU	0/77	

Q20070495ABACLV	FSCQ1565RTYDTU	0/77			
Q20070495ACACLV	FSCQ1565RTYDTU	0/77			
<b>Test: (High Temperature Storage Life)</b>					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20070495AAHTSL	FSCQ1565RTYDTU	0/77	0/77	0/77	
Q20070495ABHTSL		0/77	0/77	0/77	
Q20070495ACHTSL		0/77	0/77	0/77	
<b>Test: (Temperature Humidity Biased Test)</b>					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20070495AATHBT		0/77	0/77	0/77	
Q20070495ABTHBT		0/77	0/77	0/77	
Q20070495ACTHBT		0/77	0/77	0/77	
<b>Test: -65C, 150C (Temperature Cycle)</b>					
Lot	Device	500-CYCLES			Failure Code
Q20070495AATMCL1	FSCQ1565RTYDTU	0/77			
Q20070495ABTMCL1	FSCQ1565RTYDTU	0/77			
Q20070495ACTMCL1	FSCQ1565RTYDTU	0/77			
<b>Test: 130C (Highly Accelerated Stress Test)</b>					
Lot	Device	96-HOURS			Failure Code
Q20070495AAHAST1	FSCQ1565RTYDTU	0/77			
Q20070495ABHAST1	FSCQ1565RTYDTU	0/77			
Q20070495ACHAST1	FSCQ1565RTYDTU	0/77			

Product Id Description :

Affected FSIDs :

FS6M07652RTCTU	FS6M07652RTCTU_NL	FS6M07652RTCYDT
FS6M07652RTCYDT_NL	FS6M12653RTCYDT	FS6X1220RTYDTU
FS6X1220RTYDTU_NL	FSCM0765RC	FSCQ0565RTYDTU
FSCQ0565RTYDTU_NL	FSCQ0765RBTYDTU	FSCQ0765RBTYDTU_NL
FSCQ0765RCTYDTU	FSCQ0765RTSYDTU	FSCQ0765RTYDTU
FSCQ0765RTYDTU_NL	FSCQ0965RTYDTU	FSCQ0965RTYDTU_NL
FSCQ1265RTSYDTU	FSCQ1265RTYDTU	FSCQ1265RTYDTU_NL
FSCQ1465RTYDTU	FSCQ1465RTYDTU_NL	FSCQ1565RTSYDTU
FSCQ1565RTYDTU	FSCQ1565RTYDTU_NL	KA5Q0565RTYDTU
KA5Q0740RTYDTU	KA5Q0765RTHYDTU	KA5Q0765RTYDTU
KA5Q12656RTHYDT	KA5Q12656RTYDTU	